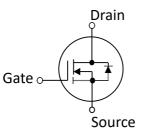


## SPQ2R4N150WP

### 150V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability
- 100% CP Probing

### **SYMBOL**



Electrical Characteristics in C/P Test (T <sub>J</sub> at 25 °C)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	150	ı	_	٧	$V_{GS} = 0V, I_D = 250 \mu A$
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	2.0	2.4	mΩ	$V_{GS} = 10V, I_D = 5A(1)$
V <sub>GS (th)</sub>	Gate Threshold Voltage	3		4.6	>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source Leakage Current	_		1	μA	V <sub>DS</sub> =150V, V <sub>GS</sub> =0V
I <sub>GSS</sub>	Gate-to-Source Leakage Current	-100		100	nA	$V_{DS} = 0V$ , $V_{GS} = \pm 20V$
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55°C to 150°C Max.				

Mechanical Data	Die Drawing			
Chip Size <sup>(2)</sup>	7920 μm X 5420 μm	5420 um		
Gate Pad Size	741 µm X 741 µm			
Source Pad Size	7600 μm X 2418 μm			
Scribe Line Width	60 μm			
Wafer Thickness	100 µm	7920.25 um 7599.7 um 7599.7 um		
Wafer Diameter	200 mm	um j		
Gross Die	609 EA			
Source Metallization	Al-Cu (4µm typical)	2417,925 um		
Drain Metallization	Ti-Ni-Ag	2417.925 um		
Passivation	Yes	741.15 um		
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C			

<sup>(1)</sup> Pulse Width tp = < 1 mS, Duty Cycle < 2%.

<sup>(2)</sup> Chip size not include scribe line.

Specific Assembly Info	Die Drawing		
Package Type	TO247	5420 um	
Die Attach Method	Soft solder		
Soft Solder Composition	Pb,Sn,Ag	7920.25 um 7599.7 um 7599.7 um 6760.025 u	
Gate Wire Bonding	Al, 5 mil x1	3	
Source Wire Bonding	Al, 20 mil x 4	2417.925 um	
Molding Compound Manufacturer	G700HF	741.15 um	
Solder Plating Composition	Pure Tin		

	Pos	ition	Bonding Diagram Top View
	X (um)	Y (um)	ТОР
ZERO	0	0	55
TOP	7920.25	5420	. \$4
S1	160.275	160.275	53
S2	6920.3	921.425	S2 G2 G1
S3	7759.975	2578.2	ZERO
S4	160.275	2841.8	
S5	7759.975	5259.725	
G1	7134.3	44.275	
G2	7875.975	785.425	



# SPQ2R4N150WP

Electrical Characteristics in F/T Test (T」at 25 °C)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I <sub>DSS</sub>	Drain-to-Source Leakage Current	_	_	1	μΑ	V <sub>DS</sub> =150V, V <sub>GS</sub> =0V
I <sub>GSSF</sub>	Gate-to-Source Leakage Current	_	_	100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =+20V
I <sub>GSSR</sub>	Gate-to-Source Leakage Current	-100	_		nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =-20V
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	150	_	_	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	150	_	_	V	$V_{GS} = 0V, I_D = 1mA$
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	_	2.9	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =100A
V <sub>GS (th)</sub>	Gate Threshold Voltage	3	_	4.6	V	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$
$V_{\text{SD}}$	Drain-Source Diode Forward Voltage			1.2	٧	$V_{GS} = 0V, I_{SD} = 10A$
EAS test	IAS				А	$V_{DD} = 80V, V_{GS} = 10V, R_G = 25\Omega, L = 0.1 mH$
$T_J, T_{STG}$	Operating and Storage Temperature	-55°C to 150°C Max.				



### SPQ2R4N150WP

**Preliminary Version: 0.0** 

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